



Attorney's Docket No.: 12732-211001 / US6966 IPR

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al.  
Serial No. : 10/774,700  
Filed : February 10, 2004  
Title : SEMICONDUCTOR DEVICE

Art Unit : Unknown  
Examiner : Unknown  
Confirmation No.: 8592

MAIL STOP AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT**

Supplemental to an information disclosure statement filed July 30, 2004, Applicants submit a full translation of Japan Patent No. 3408154, which was published on May 19, 2003. A copy of the reference listed on the attached form PTO-1449 is enclosed.

This statement is being filed before the receipt of a first Office action on the merits.  
Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

  
John F. Hayden  
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Date: September 20, 2004

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|   |  |  |                                       |                               |
|---|--|--|---------------------------------------|-------------------------------|
| Substitute Form PTO-1449<br>(Modified)<br><b>Information Disclosure Statement</b><br>by Applicant<br>(Use several sheets if necessary)<br>(37 CFR §1.14(b)) |  | U.S. Department of Commerce<br>Patent and Trademark Office | Attorney's Docket No.<br>12732-211001 | Application No.<br>10/774,700 |
|   |  | Applicant<br>Shunpei Yamazaki et al.                       |                                       |                               |
|   |  | Filing Date<br>February 10, 2004                           | Group Art Unit                        |                               |

**U.S. Patent Documents**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
|------------------|-----------|-----------------|------------------|----------|-------|----------|----------------------------|
|                  | AA        |                 |                  |          |       |          |                            |
|                  | AB        |                 |                  |          |       |          |                            |
|                  | AC        |                 |                  |          |       |          |                            |
|                  | AD        |                 |                  |          |       |          |                            |
|                  | AE        |                 |                  |          |       |          |                            |
|                  | AF        |                 |                  |          |       |          |                            |
|                  | AG        |                 |                  |          |       |          |                            |
|                  | AH        |                 |                  |          |       |          |                            |
|                  | AI        |                 |                  |          |       |          |                            |
|                  | AJ        |                 |                  |          |       |          |                            |
|                  | AK        |                 |                  |          |       |          |                            |

**Foreign Patent Documents or Published Foreign Patent Applications**

| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation |    |
|------------------|-----------|-----------------|------------------|--------------------------|-------|----------|-------------|----|
|                  |           |                 |                  |                          |       |          | Yes         | No |
|                  | AL        | 3408154         | 05/19/2003       | JAPAN                    |       |          | Full        |    |
|                  | AM        |                 |                  |                          |       |          |             |    |
|                  | AN        |                 |                  |                          |       |          |             |    |
|                  | AO        |                 |                  |                          |       |          |             |    |
|                  | AP        |                 |                  |                          |       |          |             |    |

**Other Documents (include Author, Title, Date, and Place of Publication)**

| Examiner Initial | Desig. ID | Document |
|------------------|-----------|----------|
|                  | AQ        |          |
|                  | AR        |          |
|                  | AS        |          |
|                  | AT        |          |

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.